Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/661,687	VERBANIC ET AL.
Examiner	Art Unit

2834

Nguyen N. Hanh

	SEARCHED				
Class	Subclass	Date	Examiner		
310	91	4/26/2005	HN		
310	260	4/26/2005	HN		
310	270	4/26/2005	HN		

רָאוּ	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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